## SUPPLEMENTARY INFORMATION

## Semi-conjugated Acceptor Based Polyimides as the Electrets for Nonvolatile Transistor Memory Devices

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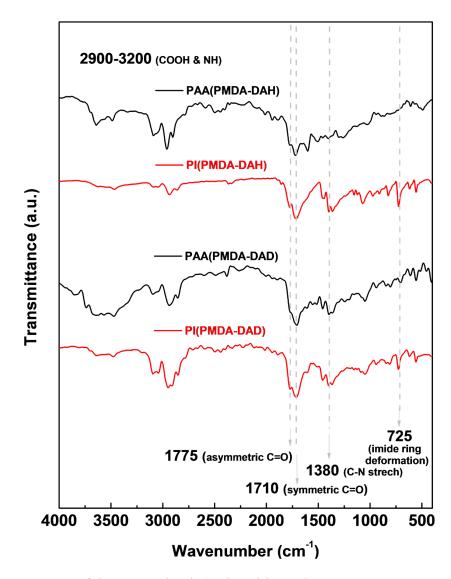
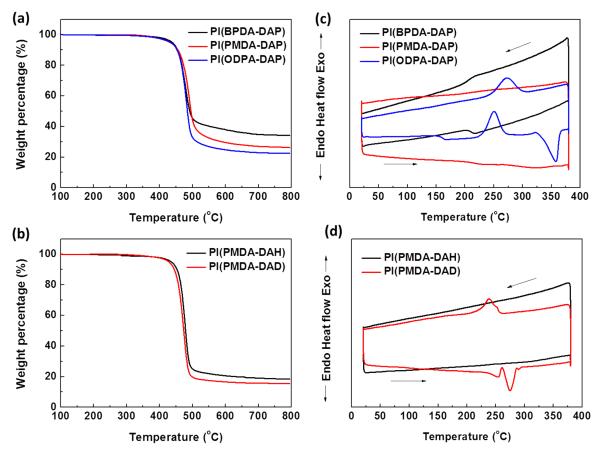
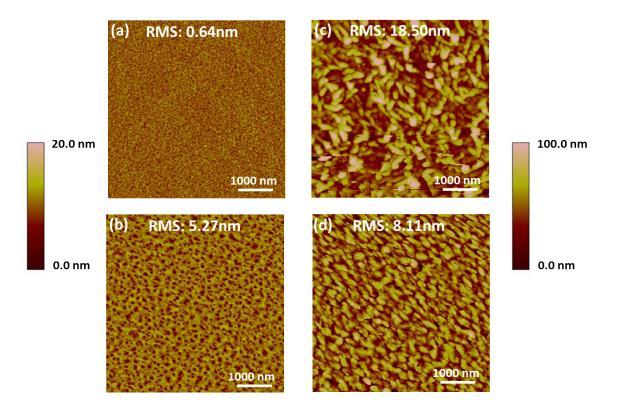


Figure S1. IR spectra of the targeted poly(amic acid)s and PI(PMDA-DAH) and PI(PMDA-DAD).



**Figure S2.** (a)-(b) TGA and (c)-(d) DSC curves of the studied PIs at a heating rate of 10°C/min and 5°C/min under nitrogen atmosphere, respectively.



**Figure S3.** AFM topographic surface images of (a) **PI(PMDA-DAH)** and (b) **PI(PMDA-DAD)** on bare SiO<sub>2</sub> substrates and the atop pentacene on (c) **PI(PMDA-DAH)** and (d) **PI(PMDA-DAD)**.

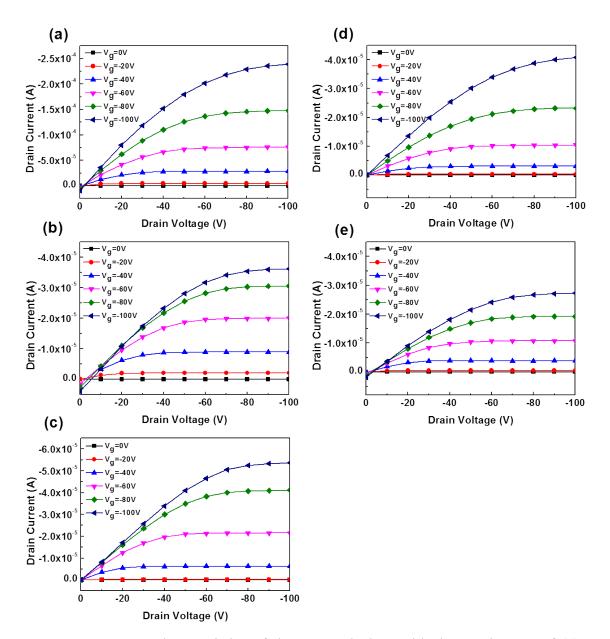


Figure S4. Output characteristics of the OFET devices with the PI electrets of (a) **PI(BPDA-DAP)**, (b) **PI(PMDA-DAP)**, (c) **PI(ODPA-DAP)**, (d) **PI(PMDA-DAH)**, and (e) **PI(PMDA-DAD)**.

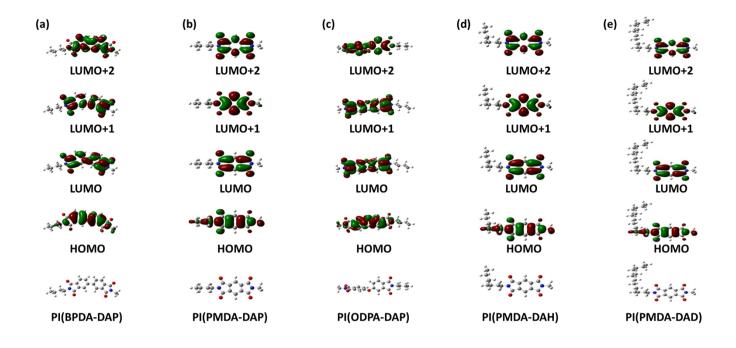


Figure S5. Molecular orbitals of (a) PI(BPDA-DAP) , (b) PI(PMDA-DAP) , (c) PI(ODPA-DAP) , (d) PI(PMDA-DAH) and (e) PI(PMDA-DAD).

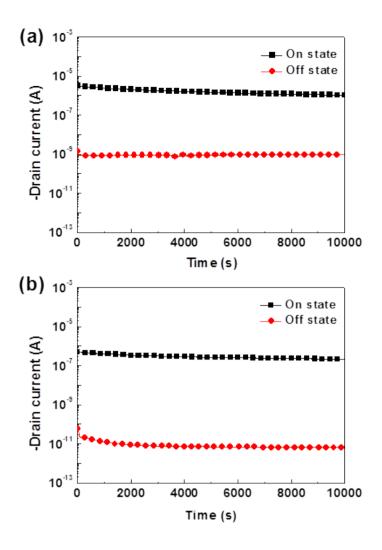
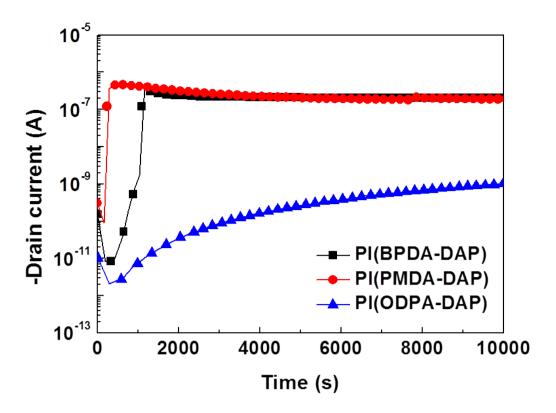


Figure S6. Retention time of the pentacene OFET memory devices with (a) **PI(PMDA-DAH)** and (b) **PI(PMDA-DAD)** as electrets at  $V_g = 0V$ .



**Figure S7.** Retention time testing of the OFET memory devices based upon pentacene thin film with **PI(BPDA-DAP)**, **PI(PMDA-DAP)** and **PI(ODPA-DAP)** as electrets at the gate voltage of 15V within 10<sup>4</sup> s.

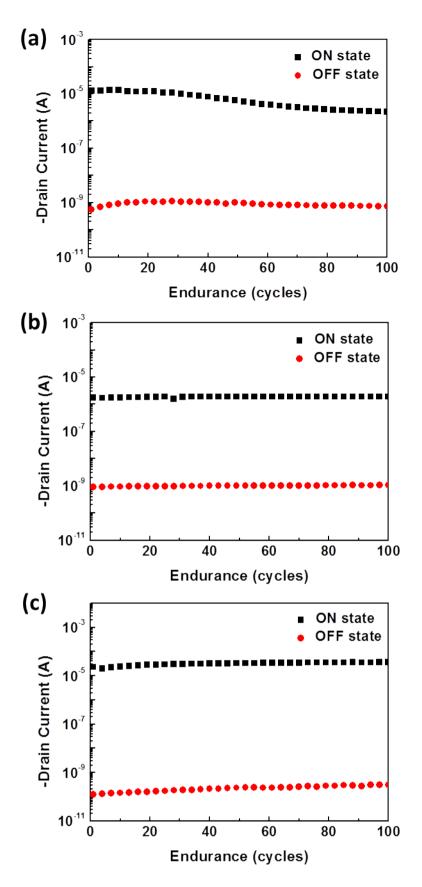


Figure S8. Endurance of the memory devices with (a) PI(BPDA-DAP), (b) PI(PMDA-DAP), and (c) PI(ODPA-DAP) as electrets.